

4/17/2013



RELIABILITY MONITOR REPORT
FOR

MFN DiMOS 200 (DM200)

MAXIM INTEGRATED

160 RIO ROBLES
SAN JOSE, CA 95134

This Report was prepared by
MAXIM INTEGRATED Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX14808ETK+	MAX14850ASE+	MAX4968AECM	MAX4986ECM+
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 70606 QUANTITY: 544 FAILS: 0 FITS: 1.6

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2012 and 3/31/2013 .

Process Information:

Process Description: MFN DiMOS 200 (DM200)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1147	MAX14850ASE+	135°C	192 HRS	80	0	JAAI0Q002EQ
HIGH TEMP OP LIFE	1211	MAX4986ECM+	135°C	500 HRS	77	0	JZMZG2016B
HIGH TEMP OP LIFE	1214	MAX14808ETK+	135°C	1000 HRS	78	0	JAEM3Q001CA
HIGH TEMP OP LIFE	1220	MAX4968AECM+	135°C	500 HRS	77	0	JZMZG2019A
HIGH TEMP OP LIFE	1220	MAX4968AECM+	135°C	500 HRS	76	0	JZMZG2020B
HIGH TEMP OP LIFE	1229	MAX14808ETK+	135°C	1000 HRS	79	0	JAHP5Q002CA
HIGH TEMP OP LIFE	1239	MAX14808ETK+	135°C	1000 HRS	77	0	JAHP5Q003CA
Total:						0	

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